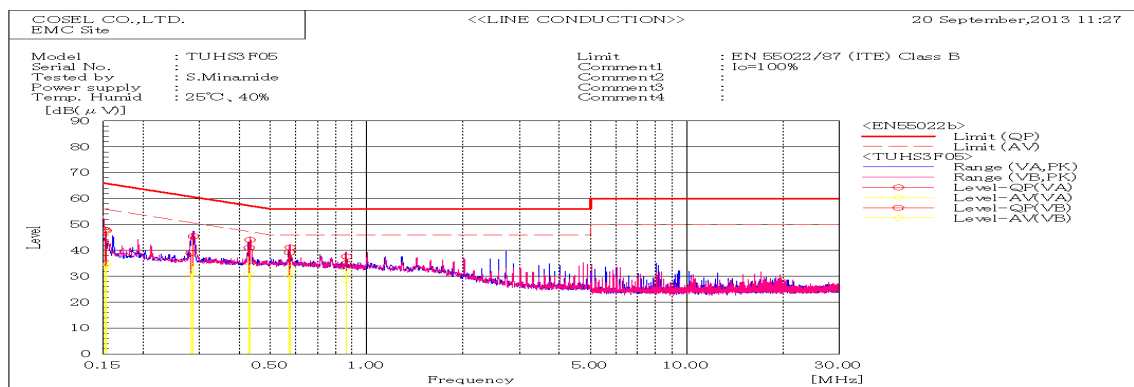
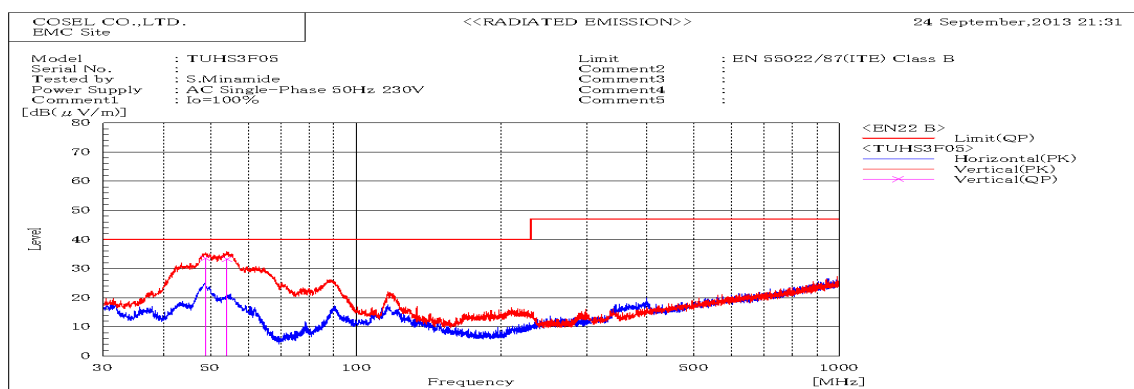


## DATA SHEET

DATA SHEET		Date	16-Dec-13
Model	TUHS3F05	Temp.	25 degreeC
Test	EMI	Humid.	40 %RH
	Line conduction & Radiated emission	Tested by	S.Minamide



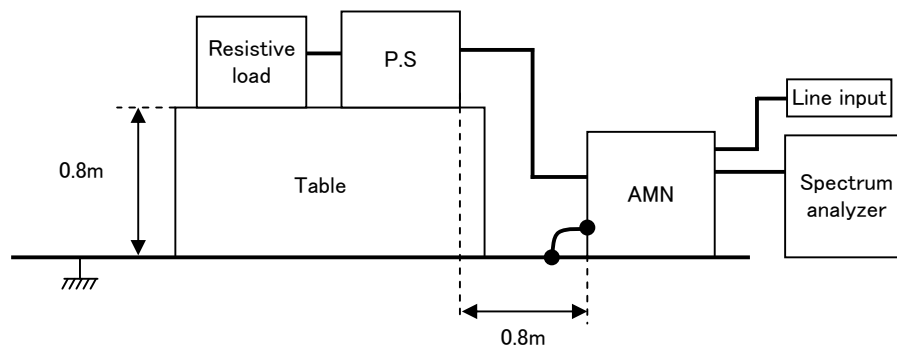
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.15185		VA	27.7	13.5	20.3	48.0	33.8	65.9	55.9	17.9	22.1	Pass	
0.15319		VB	27.4	14.5	20.2	47.6	34.7	65.8	55.8	18.2	21.1	Pass	
0.28183		VB	18.4	10.9	20.1	19.0	31.0	60.8	50.8	21.8	19.8	Pass	
0.28715		VA	25.3	13.8	20.1	45.4	33.9	60.6	50.6	15.2	16.7	Pass	
0.42885		VA	20.9	11.1	20.1	41.0	31.2	57.3	47.3	16.3	16.1	Pass	
0.43146		VB	24.0	14.6	20.1	44.1	34.7	57.2	47.2	13.1	12.5	Pass	
0.5733		VB	21.1	13.0	20.1	41.2	33.1	56.0	46.0	14.8	12.9	Pass	
0.57702		VA	19.1	10.2	20.1	39.2	30.3	56.0	46.0	16.8	15.7	Pass	
0.85998		VA	14.7	8.4	20.2	34.9	28.6	56.0	46.0	21.1	17.4	Pass	
0.86544		VB	17.4	11.9	20.2	37.6	32.1	56.0	46.0	18.4	13.9	Pass	



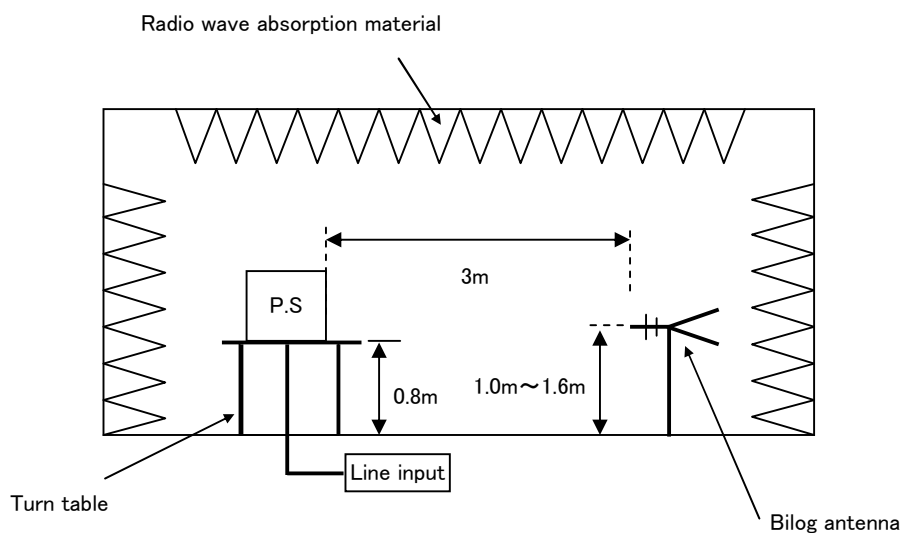
Frequency MHz	Polariz ation	Stabili ty	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
48.768	V	Stable	56.8		-23.3	33.5		40	6.5	Pass	102	82	
54.085	V	Stable	57		-23.8	33.2		40	6.8	Pass	103	166	

DATA SHEET		Date	16-Dec-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide

## 1. Line conduction



## 2. Radiated emission



## Conditions

Test: EMI

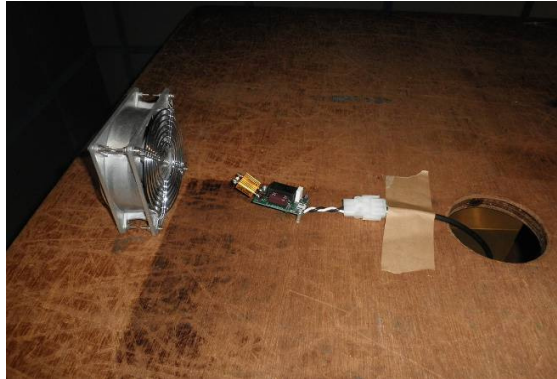
Model Name: TUHS3F□□

### ○ Photographs of Test Set-Up

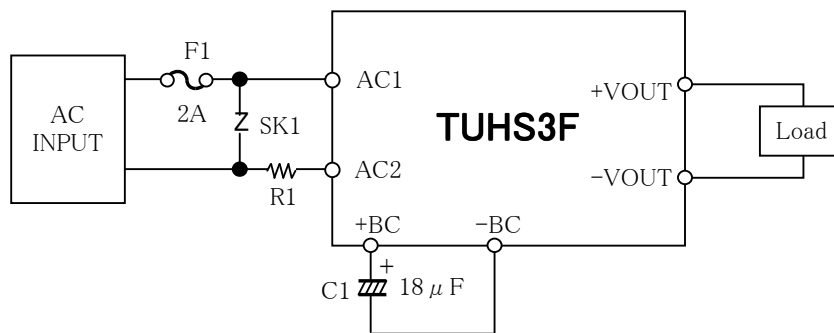
#### LINE CONDUCTION



#### RADIATED EMISSION



### ○ Test circuit



F1: SLT250V2A (Nippon Seisen)  
 R1: 1K100JA (TAMURA THERMAL DEVICE)  
 SK1: TND10V-511K (NIPPON CHEMI-CON)

2A  
 10Ω

Fig.1 Testing circuitry